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Total Number of Pages in This Submission

Application Number	10/612,133
Filing Date	07/02/2003
First Named Inventor	Miles et al.
Art Unit	2878
Examiner Name	Thanh X. Luu
Attorney Docket Number	SHP-PT077

### ENCLOSURES (Check all that apply)

<input type="checkbox"/> Fee Transmittal Form <input type="checkbox"/> Fee Attached <input type="checkbox"/> Amendment/Reply <input type="checkbox"/> After Final <input type="checkbox"/> Affidavits/declaration(s) <input type="checkbox"/> Extension of Time Request <input type="checkbox"/> Express Abandonment Request <input checked="" type="checkbox"/> Supplemental Information Disclosure Statement  <input type="checkbox"/> Certified Copy of Priority Document(s) <input type="checkbox"/> Reply to Missing Parts/Incomplete Application <input type="checkbox"/> Reply to Missing Parts under 37 CFR 1.52 or 1.53	<input type="checkbox"/> Drawing(s) <input type="checkbox"/> Licensing-related Papers <input type="checkbox"/> Petition <input type="checkbox"/> Petition to Convert to a Provisional Application <input type="checkbox"/> Power of Attorney, Revocation Change of Correspondence Address <input type="checkbox"/> Terminal Disclaimer <input type="checkbox"/> Request for Refund <input type="checkbox"/> CD, Number of CD(s) _____ <input type="checkbox"/> Landscape Table on CD	<input type="checkbox"/> After Allowance Communication to TC <input type="checkbox"/> Appeal Communication to Board of Appeals and Interferences <input type="checkbox"/> Appeal Communication to TC (Appeal Notice, Brief, Reply Brief) <input type="checkbox"/> Proprietary Information <input type="checkbox"/> Status Letter <input checked="" type="checkbox"/> Other Enclosure(s) (please identify below): Form PTO-1449; 13 references
<div>Remarks</div>		

### SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT

Firm Name	VOLPE AND KOENIG, P.C.		
Signature	<i>Ryan W. O'Donnell</i>		
Printed name	Ryan W. O'Donnell		
Date	March 22, 2007	Reg. No.	53,401

### CERTIFICATE OF TRANSMISSION/MAILING

I hereby certify that this correspondence is being facsimile transmitted to the USPTO or deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Mail Stop AF, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on the date shown below:

Signature	<i>Ryan W. O'Donnell</i>		
Typed or printed name	Ryan W. O'Donnell	Date	March 22, 2007

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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In the PATENT APPLICATION of:

Mervyn J. Miles et al.

Our File: SHP-PT077

Application No.: 10/612,133

Date: March 22, 2007

Confirmation No.: 3323

Filed: July 2, 2003

For: RESONANT SCANNING PROBE  
MICROSCOPE

Group: 2878

Examiner: Thanh X. Luu

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
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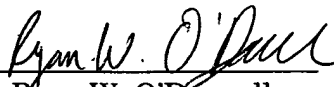
Sir:

Further to Applicants' Duty of Disclosure pursuant to 37 C.F.R. §1.56, Applicants wish to bring to the Examiner's attention the material cited on the enclosed PTO-1449 form. Pursuant to 37 C.F.R. §1.98(a)(2)(ii), copies of the cited U.S. publications and/or patent documents have not been included.

It is respectfully requested that the Examiner consider these documents and return an initialed copy of the PTO-1449 form indicating his consideration of the cited materials.

Respectfully submitted,

Miles et al.

By   
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FORM PTO-1449

ATTY. DOCKET NO.  
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10/612,133U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEAPPLICANT  
Mervyn J. Miles et al.INFORMATION DISCLOSURE  
STATEMENT BY APPLICANTFILING DATE  
07/02/2003GROUP  
2878

(Use several sheets if necessary)

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	3,702,398	11/1972	Van-Essen et al.			
	AB	5,412,980	05/1995	Elings et al.			
	AC	5,566,159	10/1996	Shapira			
	AD	6,094,971	08/2000	Edwards et al.			
	AE	6,236,783	05/2001	Mononobe et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
	AI	0	8	6	4	8	9	9	9/1998	Europe				
	AF	5	4	5	5	3	8	A1	09/2003	Europe				
	AG	1	9	5	3	1	4	66	10/1996	Germany				
	AH	1	9	8	5	2	8	33	5/2000	Germany				
	AJ	2	0	0	1	4	5	19	1/2001	Japan				X*
	AK	2	0	0	0	19	97	36	7/2000	Japan				X*

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AL	M. Antognozzi, et al., A New Method To Measure The Oscillation Of A Cylindrical Cantilever: "The Laser Reflection Detection System," 04/2000, Review of Scientific Instruments, Volume 71, No. 4, pp 1689-1694
AM	S.K. Sekatskii, et al., Time-Gated Scanning Near-Field Optical Microscopy, 10/2/2000, Applied Physics Letters, Volume 77, No. 14, pp 2089-2091
AN	S.H. Simpson, et al., Analysis Of The Effect Arising From The Near-Field Optical Microscopy Of Homogeneous Dielectric Slabs, 09/1/2001, Optics Communications 196, pp 17-31
AO	Khaled Karrai, et al., Piezoelectric tip-sample control for near field optical microscopes, 04/3/1995, American Institute of Physics, Vol. 66, No. 14, pp 1842-1844
AP	Claire E. Jordan, et al., Removing optical artifacts in near-field scanning optical microscopy by using a three-dimensional scanning mode, 09/1/1999, Journal of Applied Physics, Vol. 86, No. 5, pp 2785-2789
AQ	Oshikane et al., Scanning Near-Field Optical Microscope With A Small Spherical Protrusion Probe Excited With WGM Resonances, Optical Memory & Neural Networks 2000, Vol. 9, No. 3, pp 147-168
AR	Oshikane et al., 3D-FDTD and experimental analysis of a resonant microcavity probe for high-resolution SNOM, Physics Devices & Information Processing, 07/1999, Vol. 3791, pp 57-62

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

\*Abstract Only